

**Search Notes**

Application/Control No.

10/618,883

Examiner

John Chavis

Applicant(s)/Patent under  
Reexamination

CHEN, CHIH-WEI

Art Unit

2193

**SEARCHED**

Class	Subclass	Date	Examiner
717	170	6/7/2006	JC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
West (IBM TDB, Derwent, EPO, JPO, PGPUBS, USPAT) anded with word search	6/7/2006	JC